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Notice of Allowability	Application No.	Applicant(s)	
	10/707,451	SCHMIDT, MARKUS	
	Examiner	Art Unit	
	John A. McPherson	1756	
The MAILING DATE of this communication appears on the cover sheet with the correspondence address All claims being allowable, PROSECUTION ON THE MERITS IS (OR REMAINS) CLOSED in this application. If not included herewith (or previously mailed), a Notice of Allowance (PTOL-85) or other appropriate communication will be mailed in due course. THIS NOTICE OF ALLOWABILITY IS NOT A GRANT OF PATENT RIGHTS. This application is subject to withdrawal from issue at the initiative of the Office or upon petition by the applicant. See 37 CFR 1.313 and MPEP 1308.			
1. This communication is responsive to <u>12/15/03</u> .			
2. The allowed claim(s) is/are <u>1-15</u> .			
3.			
Attachment(s) 1. ☑ Notice of References Cited (PTO-892) 2. ☐ Notice of Draftperson's Patent Drawing Review (PTO-948) 3. ☐ Information Disclosure Statements (PTO-1449 or PTO/SB/O Paper No./Mail Date 4. ☐ Examiner's Comment Regarding Requirement for Deposit of Biological Material	5. ☐ Notice of Informal P 6. ☐ Interview Summary Paper No./Mail Da 7. ☐ Examiner's Amendr 8. ☑ Examiner's Stateme 9. ☐ Other	(PTO-413), te ment/Comment	

Application/Control Number: 10/707,451

Art Unit: 1756

Pertinent Prior Art

The prior art made of record and not relied upon is considered pertinent to applicant's disclosure.

US 6,543,030 discloses a method for fabricating micron and sub-micron features within a polymer layer comprising directly imprinting small features with an optical mechanical stamp, and creating large features by exposing the surface of selected areas to UV radiation.

US 6,569,575 discloses an optical lithography scheme making use of light coupling structures.

US 2005/0130074 discloses a method for the manufacture of micro structures utilizing a combination of photolithographic mask technology and micro contact printing.

US 6,671,034 discloses a method for producing a two dimensional pattern having line widths less than the wavelength of an exposure light comprising the steps of placing a proximity exposure pattern on a waveguide or on a portion of a light source, aligning a fabrication object having a photosensitive film in proximity of the proximity field exposure pattern, injecting a light into the proximity field exposure pattern so as to imprint the proximity field exposure pattern on the photosensitive material by means of an evanescent filed formed between the proximity filed exposure pattern and the photosensitive film.

US 6,187,482 discloses a method comprising the steps of disposing a mask provided with minute aperture patterns opposite to an object, irradiating the mask with light from its back side, and exposing the object to the minute aperture patterns,

Page 2

Art Unit: 1756

whereby the patterns are transferred thereto, by evanescent light that emerges from the minute aperture patterns.

Allowable Subject Matter

The following is an examiner's statement of reasons for allowance:

In a method for the manufacture or sub-wavelength structures on a substrate as set forth in claim 1 of the present invention, the prior art does not teach or suggest the step of creating evanescent waves to expose the photoresist.

Any comments considered necessary by applicant must be submitted no later than the payment of the issue fee and, to avoid processing delays, should preferably accompany the issue fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for Allowance."

Any inquiry concerning this communication or earlier communications from the examiner should be directed to John A. McPherson whose telephone number is (571) 272-1386. The examiner can normally be reached on Monday through Friday, 8:00 AM to 4:30 PM.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Mark Huff can be reached on (571) 272-1385. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

Application/Control Number: 10/707,451

Art Unit: 1756

Page 4

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John A. McPherson Primary Examiner Art Unit 1756

JAM 5/1/06